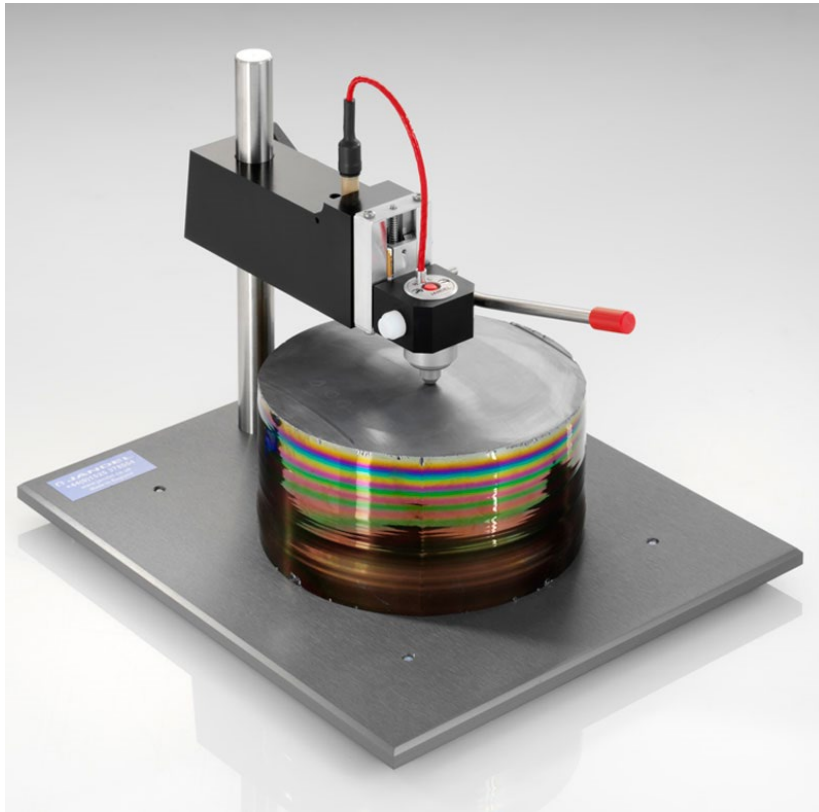


Jandel Engineering Limited



Jandel Multiheight Probe stand

DCMIW offers the Multiheight Probe stand as a solution for a wide variety of measurements. The probe mechanism can be raised and lowered meaning that samples ranging in thickness from thin films to large ingots can be measured.

The Multiheight Probe can be supplied with 4 optional mounting holes which can accommodate optional mounting accessories such as an 8 inch wafer table or micropositioning X-Y stage.

Max. sample size	Samples up to 250mm diameter (300mm option at no extra cost)
Max. sample thickness	Samples up to 250mm high can be measured (higher on request)
Microswitch	Prevents current flow when probe is not in contact with sample
Manual control	Simple lever operation for probe contact and removal
Simple set up	Single wire connects probe stand and measurement electronics
Mounting holes	Optional sample tables are available

System configuration

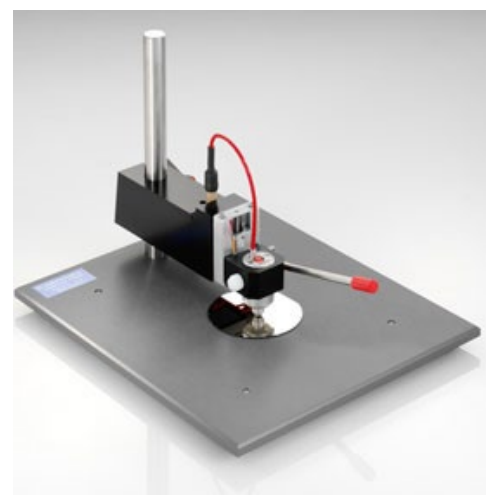
Component parts:

- A. Measurement base - 1 pc
- B. Multiheight assembly - 1 pc
- C. Multiheight column - 1 pc
- D. Four point probe head - 1 pc
- E. Connecting cable - 1 pc

System footprint

- A. Multiheight Probe base: 250mm W x 290mm L x 8mm H
(320mm x 370mm x 8mm option)
- B. Multiheight Probe assembly: 60mm W x 280mm L x 80mm H
(60mm x 330mm x 80mm option)
- C. Multiheight column: 19mm diameter, 200mm L (up to 1m on request)

Note: Our Multiheight Probe stand includes a cylindrical four point probe head. For more information on cylindrical probe heads and the specifications available, please see our cylindrical probe head datasheet.



If you require any further information on the Jandel Multiheight Probe stand, please do not hesitate to contact us using the details below.